

**Search Notes**

Application/Control No.

10/781,699

Examiner

Y. J. Han

Applicant(s)/Patent under  
Reexamination

EGUCHI ET AL.

Art Unit

2838

**SEARCHED**

Class	Subclass	Date	Examiner
363	16		
	17		
	21.01		
	65		
	68		
	71		
	75		
	98		
	132	8/05	gH
Search updated 1/06			gH

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR